



# LM80 Test Report

IES LM-80-08 Approved Method for Measuring Lumen Maintenance of LED Light Sources

## Samsung Electronics LED Business Report

Report No. : SLED-19-028-R01  
 Test Initiated Date : 2015.02.13  
 Test End Date : 2017.03.28  
 Report Issued Date : 2019.05.31  
 Report Revised Date : 2019.11.13

<p><b>Test result reported for</b></p> <p>SAMSUNG ELECTRONICS LED BUSINESS Lighting Marketing Group</p>	<p><b>Testing performed by</b></p> <p><b>SAMSUNG ELECTRONICS LED BUSINESS</b> 1, Samsung-ro, Giheung-gu, Yongin-si, Gyeonggi-do 17113, Korea e-mail) kwon.sc@samsung.com</p>
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<p><b>Test Personal Name &amp; Signatory</b></p>	<p><b>Approval Name &amp; Signatory</b></p>

**SAMSUNG ELECTRONICS LED BUSINESS Executive Vice President**  
**Accredited by KOLAS, Republic of KOREA**

The above testing certificate is the accredited testing items by Korea Laboratory Accreditation Scheme, which signed the ILAC-MRA.

※ If you need confirmation about the authenticity of the test report, please contact the above contact information.

## ■ Revision History ■

Data	Revision History	Writer	
		Drawn	Approved
2019.05.31	New Version(13kh)	K.Y.KWAK	D.S.PARK
2019.11.13	Extended Evaluation Time(17kh)	K.Y.KWAK	D.S.PARK

## ■ Test Summary ■

Life test condition			Summary of result		
Test condition	Current (mA)	Case temperature (°C)	Test duration (h)	Average lumen maintenance (%)	Maximum chromaticity shift ( $\Delta u'v'$ )
1	700	54.8	17 000	97.7	0.001 3
2	700	85.0	17 000	97.3	0.001 4
3	700	104.7	17 000	97.0	0.002 2

### 1. Number of LED light sources tested

#### 1) Sample size

- 20 Packages tested at actual case temperature 54.8 °C
- 20 Packages tested at actual case temperature 85.0 °C
- 20 Packages tested at actual case temperature 104.7 °C

#### 2) Sampling method

- Minimum three manufacturing lots with each manufacturing lot built from different wafer lots built on non-consecutive days.

### 2. Description of LED light sources

- Tested model code : SPHWH2L3D30CD4V\*\*\*
- Sample manufacturer : Samsung Electronics
- Sample Type : LED Package
- Package dimension : ( 3.5 × 3.5 ) mm
- Minimum die spacing : -
- CCT / CRI (Nominal) : 3 000 K / 70

### 3. Description of auxiliary equipment

- 1) Instrument Integrating sphere ISP1000-100
- 2) Instrument CAS140-CT
- 3) Keithley 2425 Sourcemeater

#### 4. Operating time

##### 1) Electrical condition

- Drive current : 700 mA
- Typical voltage : 2.97 V
- Total input power : 2.08 W
- Average current density per LED die : 326 mA/mm<sup>2</sup>
- Average power density per LED die : 0.97 W/mm<sup>2</sup>
- \* LED packages are driven with a constant direct current.

##### 2) Test duration

- 17 000 h

#### 5. Ambient conditions including airflow, temperature and relative humidity

The minimal airflow is maintained in chamber.

The ambient temperature around the LED packages inside chamber is controlled by air flowing and the thermocouple readings are monitored.

- Case temperature : Controlled to -2 °C
- Surrounding air temperature : Controlled to -5 °C
- Relative humidity : < 65 % R.H.

#### 6. Case temperature (Test point temperature)



**Case Temperature  
Measurement Point**

#### 7. Drive current of the LED light source during lifetime test

See Sub-clause 9.1, 9.2 and 9.3

#### 8. Initial luminous flux and forward voltage

See the table

#### 9. Lumen maintenance data for each individual LED light source

See the table























































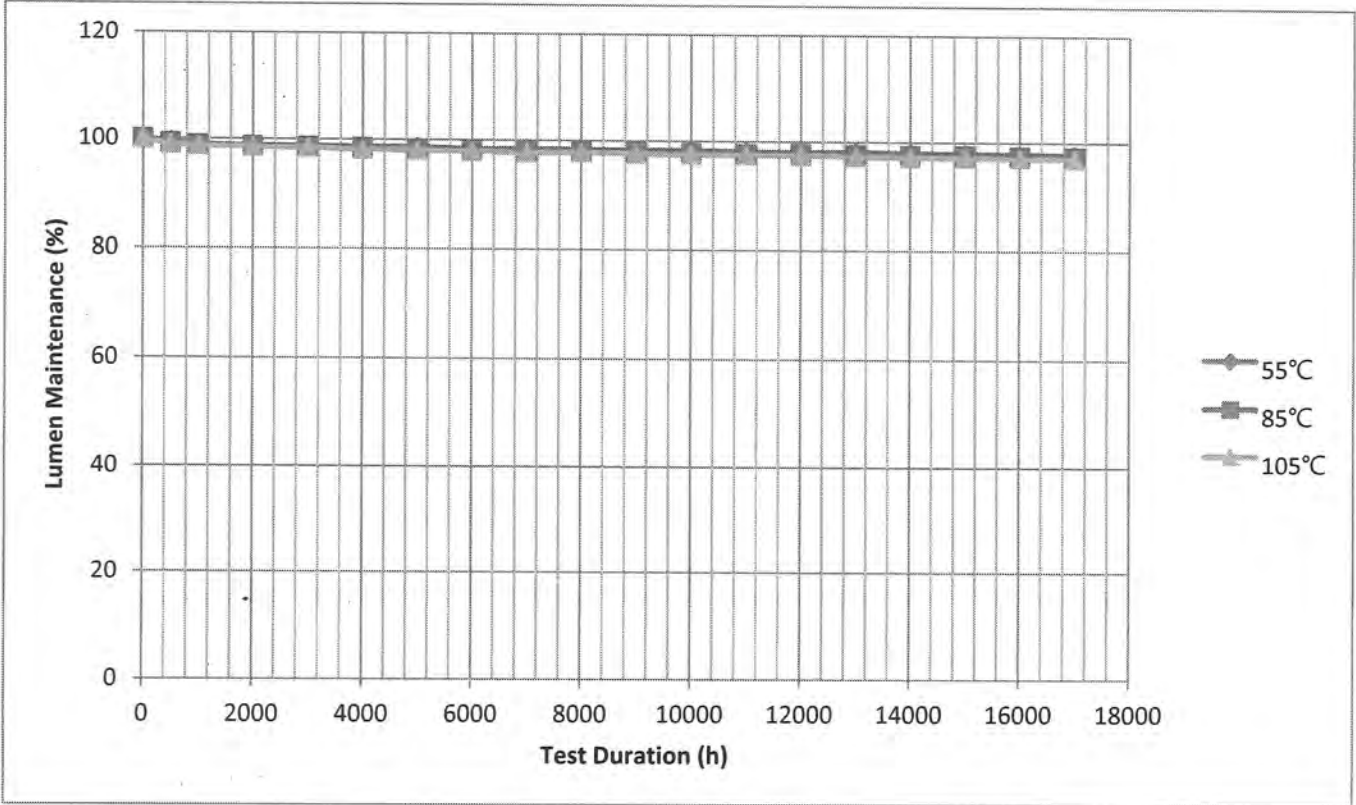




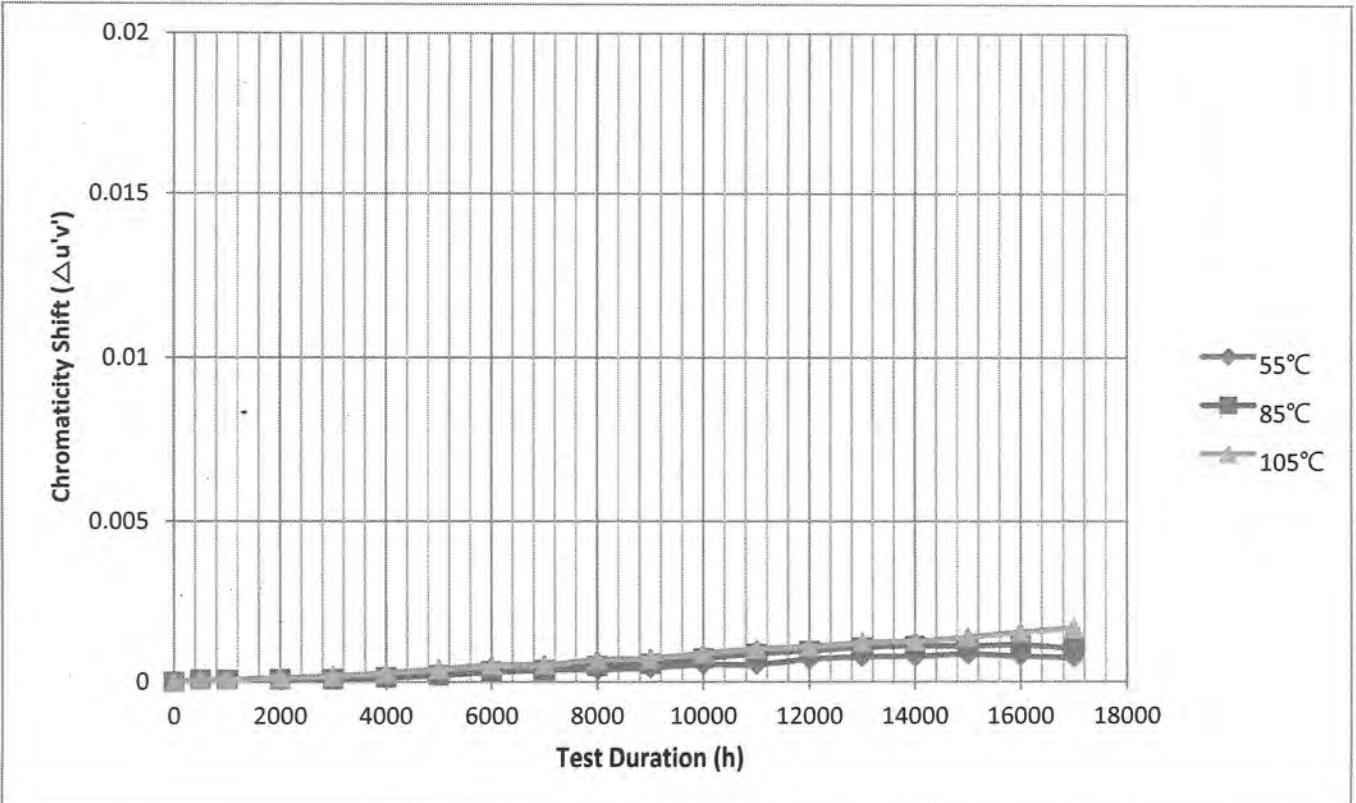


## 9.4 Chart

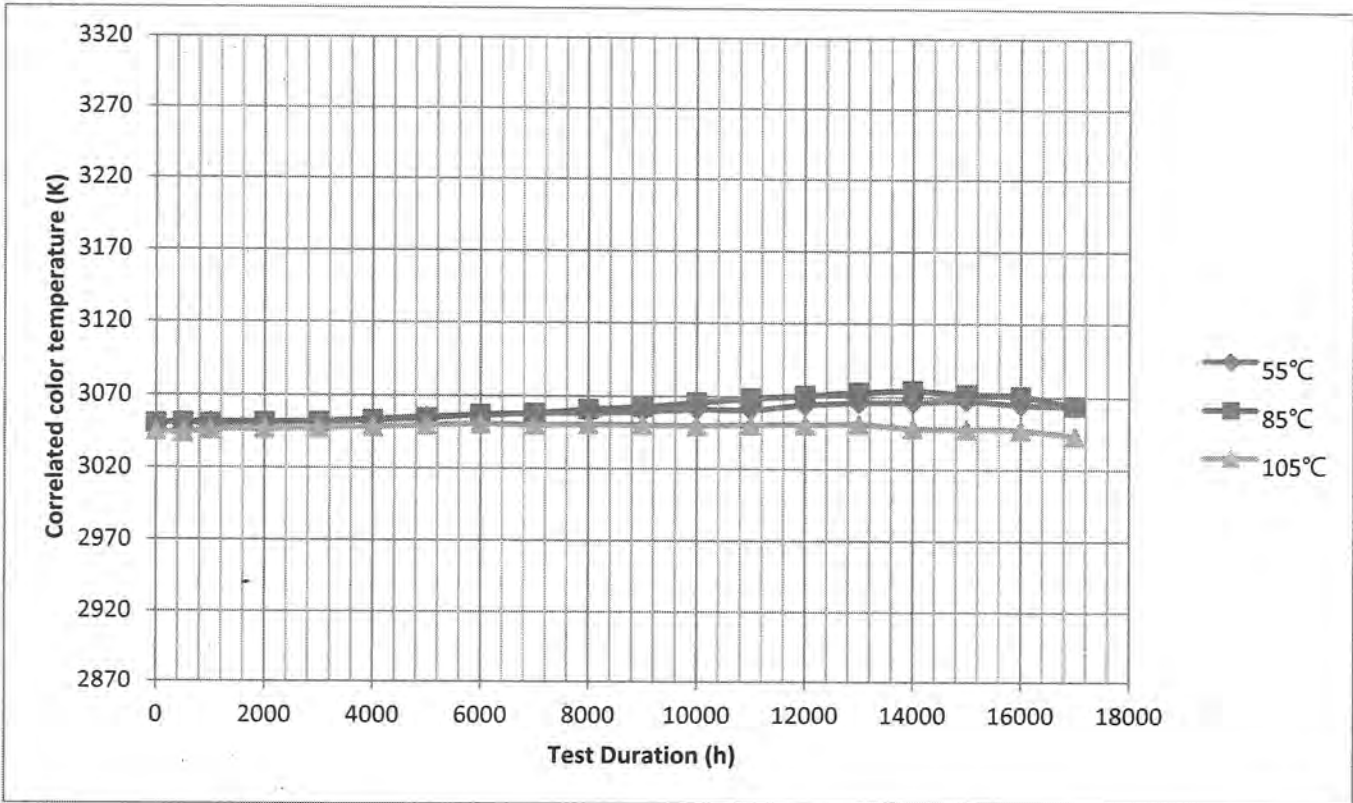
### <Lumen Maintenance>



### <Chromaticity Shift>



<CCT>



**10. Observation of failures**

No optical, Electrical or mechanical failure of any LED Package was seen during the lifetime testing.

**11. LED light source monitoring interval**

0 500 1 000 2 000 3 000 4 000 5 000 6 000 7 000 8 000  
9 000 10 000 11 000 12 000 13 000 14 000 15 000 16 000 17 000

**12. Photometric measurement uncertainty**

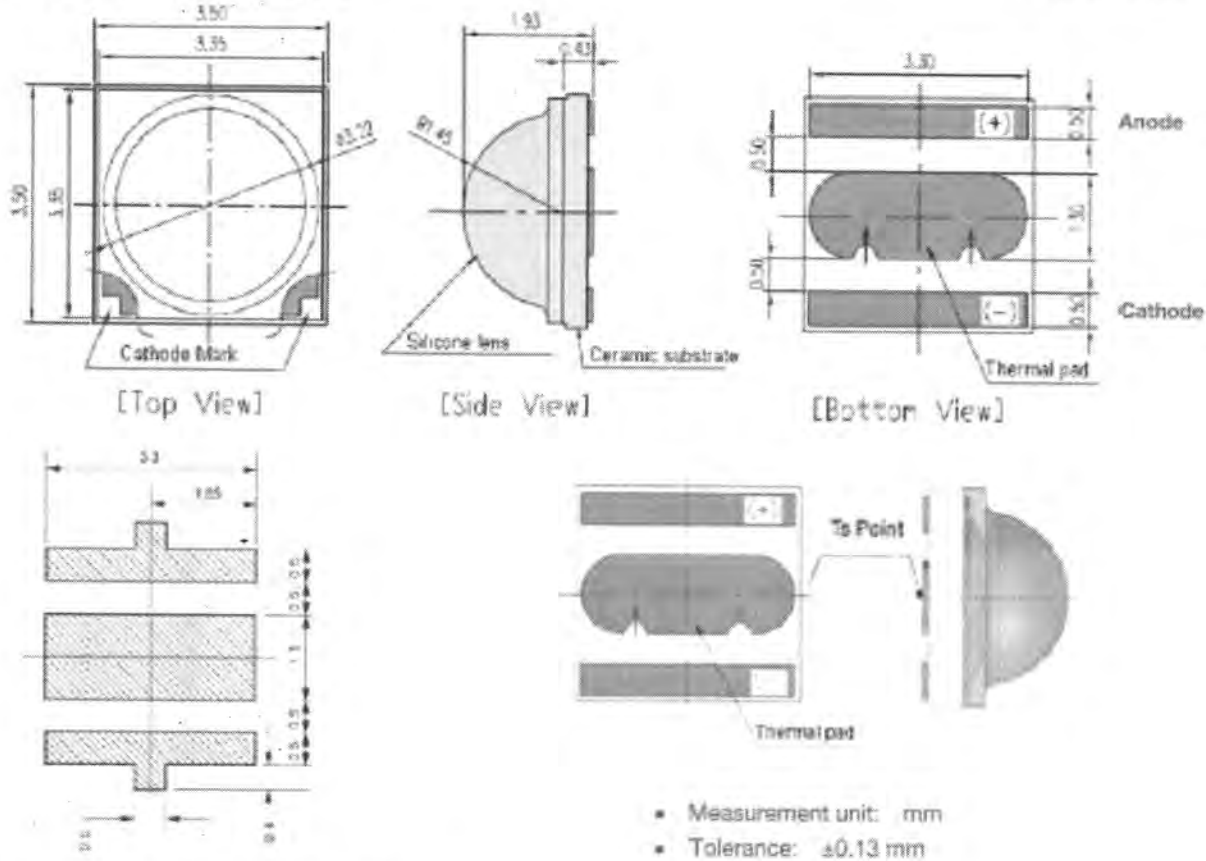
3.5%

**13. TM-21-11 Report : Projecting Long Term Lumen Maintenance of LED Light Source**

Table 1: Report at each LM-80 Test Condition							
Description of LED Light Source Tested (manufacturer, model, catalog number)		Test Condition 1 - 55°C Case Temp		Test Condition 2 - 85°C Case Temp		Test Condition 3 - 105°C Case Temp	
Sample size	20	Sample size	20	Sample size	20	Sample size	20
Number of failures	0	Number of failures	0	Number of failures	0	Number of failures	0
DUT drive current used in the test (mA)	700	DUT drive current used in the test (mA)	700	DUT drive current used in the test (mA)	700	DUT drive current used in the test (mA)	700
Test duration (hours)	17,000	Test duration (hours)	17,000	Test duration (hours)	17,000	Test duration (hours)	17,000
Test duration used for projection (hour to hour)	8,000 - 17,000	Test duration used for projection (hour to hour)	8,000 - 17,000	Test duration used for projection (hour to hour)	8,000 - 17,000	Test duration used for projection (hour to hour)	8,000 - 17,000
Tested case temperature (°C)	55	Tested case temperature (°C)	85	Tested case temperature (°C)	105	Tested case temperature (°C)	105
$\alpha$	6.432E-07	$\alpha$	6.394E-07	$\alpha$	8.715E-07	$\alpha$	8.715E-07
B	0.988	B	0.985	B	0.984	B	0.984
Reported L90(17k) (hours)	>102000	Reported L90(17k) (hours)	>102000	Reported L90(17k) (hours)	>102000	Reported L90(17k) (hours)	>102000



## 14. Dimension of samples



## Recommended Soldering Pattern

## 15. Cover models

Series Name	Model Code	CCT(K)
LH351B	SPHWH2L3D30C**V***	3000
	SPHWH2L3D30C**U***	3500
	SPHWH2L3D30C**T***	4000
	SPHWH2L3D30C**R***	5000
	SPHWH2L3D30C**Q***	5700
	SPHWH2L3D30C**P***	6500

\*\*\*\*\***END OF TEST REPORT**\*\*\*\*\*